

## G-RAD Workshop - Grenoble Radiation Testing of semiconductor devices and systems



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### **Q&A Session on limitations of current offer for radiation testing facilities**

*Thursday, 10 December 2020 10:15 (25)*

**Presenter(s) :** BOUDOU, Caroline (Institut Laue-Langevin); CAPRIA, Ennio (European Synchrotron (ESRF))

**Session Classification :** Session 3 - Harsh Environments and specific needs